TOSHIBA CCD Linear Image Sensor　CCD (Charge Coupled Device)

TCD1706DG

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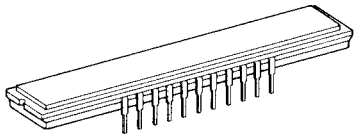
TCD1706DG

The TCD1706DG is a high sensitive and low dark current 7400 elements CCD linear image sensor.

The device contains a row of 7400 elements photodiodes which provide 24 lines/mm across a A3 size paper. The device is operated by 5.0 V pulse and 12 V power supply.



WDIP22-G-400-2.54E

Features

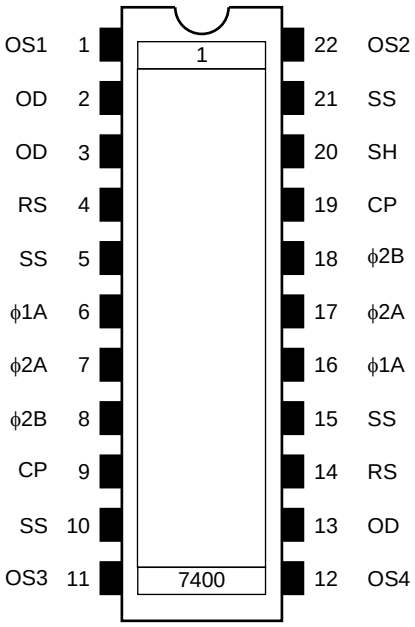
- Number of Image Sensing Elements: 7400 elements
- Image Sensing Element Size: 4.7 µm by 4.7 µm on 4.7 µm center
- Photo Sensing Region: High sensitive PN photodiode
- Clock: 2-phase (5 V)
- Power Supply Voltage: 12 V (typ.)
- Internal Circuit: Clamp circuit
- Package: 22 pin CERDIP

ABSOLUTE MAXIMUM RATINGS (Note 1)

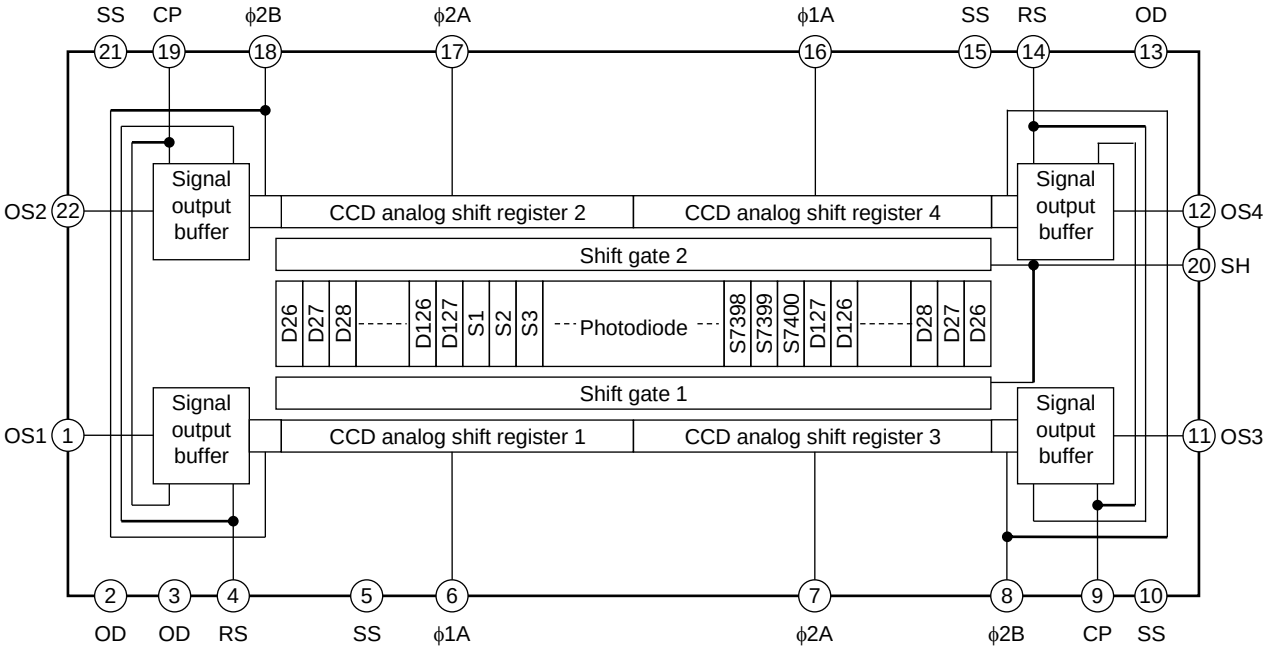
Characteristics	Symbol	Rating	Unit
Clock pulse voltage	V_{ϕ}	−0.3 to +8.0	V
Shift pulse voltage	V_{SH}		
Reset pulse voltage	V_{RS}		
Clamp pulse voltage	V_{CP}		
Power supply voltage	V_{OD}	−0.3 to +15.0	V
Operating temperature	T_{opr}	0 to 60	°C
Storage temperature	T_{stg}	−25 to +85	°C

Note 1: All voltages are with respect to SS terminals (ground).
None of the ABSOLUTE MAXIMUM RATINGS must be exceeded, even instantaneously.
If any one of the ABSOLUTE MAXIMUM RATINGS is exceeded, the electrical characteristics, reliability and life time of the device cannot be guaranteed. If the ABSOLUTE MAXIMUM RATINGS are exceeded, the device can be permanently damaged or degraded. Create a system design in such a manner that any of the ABSOLUTE MAXIMUM RATINGS will not be exceeded under any circumstances.

Pin Connections (top view)



Circuit Diagram



Pin Names

Pin No.	Symbol	Name	Pin No.	Symbol	Name
1	OS1	Output signal 1	22	OS2	Output signal 2
2	OD	Power supply	21	SS	Ground
3	OD	Power supply	20	SH	Shift gate
4	RS	Reset gate	19	CP	Clamp gate
5	SS	Ground	18	ϕ2B	Last stage transfer clock (phase 2)
6	ϕ1A	Transfer clock (phase 1)	17	ϕ2A	Transfer clock (phase 2)
7	ϕ2A	Transfer clock (phase 2)	16	ϕ1A	Transfer clock (phase 1)
8	ϕ2B	Last stage transfer clock (phase 2)	15	SS	Ground
9	CP	Clamp gate	14	RS	Reset gate
10	SS	Ground	13	OD	Power supply
11	OS3	Output signal 3	12	OS4	Output signal 4

Optical/Electrical Characteristics

Ta = 25°C, V_{OD} = 12 V, V_{ϕ} = V_{SH} = V_{RS} = V_{CP} = 5 V (pulse), f_{ϕ} = 1.0 MHz, t_{INT} (integration time) = 10 ms, light source = daylight fluorescent lamp

Characteristics	Symbol	Min	Typ.	Max	Unit	Note
Sensitivity	R	12	15	18	V/lx·s	—
Photo response non uniformity	PRNU	—	3	10	%	(Note 2)
	PRNU (3)	—	6	12	mV	(Note 8)
Saturation output voltage	V_{SAT}	1.5	2.0	—	V	(Note 3)
Saturation exposure	SE	0.08	0.13	—	lx·s	(Note 4)
Dark signal voltage	V_{DRK}	—	1	3	mV	(Note 5)
Dark signal non uniformity	DSNU	—	4	10	mV	(Note 5)
DC power dissipation	P_D	—	720	1200	mW	—
Total transfer efficiency	TTE	92	98	—	%	—
Output impedance	Z_O	—	0.2	1.0	kΩ	—
Dynamic range	DR	—	2000	—	—	(Note 6)
DC output signal voltage	V_{OS}	4.5	6.0	7.5	V	(Note 7)
DC differential error voltage	$\lvert V_{OSX} - V_{OSY} \rvert$	—	—	300	mV	(Note 9)
Random noise	$N_{D\sigma}$	—	1.0	—	mV	(Note 10)

Note 2: PRNU is defined on a single chip by the expressions below when the photosensitive surface is applied with the light of uniform illumination and uniform color temperature, where measured approximately 750 mV of signal output.

$$PRNU = \frac{\Delta X}{\overline{X}} \times 100\ (\%)$$

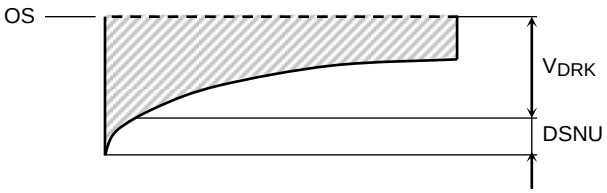
Where $\overline{X}$ is average of total signal outputs and ΔX is the maximum deviation from $\overline{X}$ under uniform illumination. (OS1)
In the case of 1850 elements (OS2, OS3 and OS4), the condition is the same as above too.

Note 3: V_{SAT} is defined as the minimum saturation output voltage of all effective pixels.

Note 4: Definition of SE:

$$SE = \frac{V_{SAT}}{R}$$

Note 5: V_{DRK} is defined as average dark signal voltage of all effective pixeis.
DSNU is defined by the difference between average value (V_{DRK}) and the maximum value of the dark voltage.

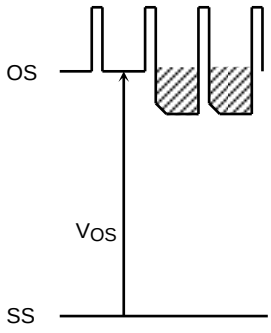


Note 6: Definition of DR:

$$DR = \frac{V_{SAT}}{V_{DRK}}$$

V_{DRK} is proportional to t_{INT} (integration time). So shorter integration time makes wider dynamic range.

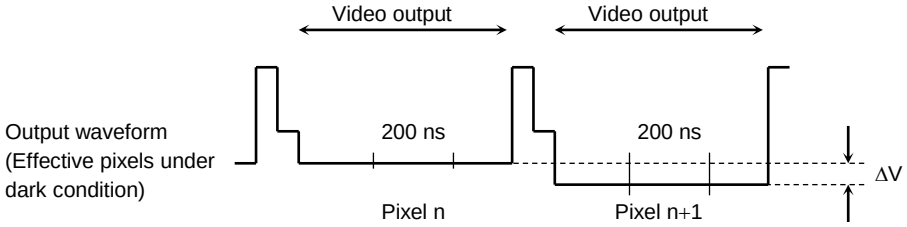
Note 7: DC output signal voltage is defined as follows.



Note 8: PRNU (3) is defined as the maximum voltage with next pixel, where measured approximately 50 mV of signal output.

Note 9: DC differential error voltage is defined as follows.
Definition of DC differential error voltage = $|V_{OSX} - V_{OSY}|$
V_{OSX}: The maximum DC output signal voltage of OS1, OS2, OS3, OS4.
V_{OSY}: The minimum DC output signal voltage of OS1, OS2, OS3, OS4.

Note 10: Random noise is defined as the standard deviation (sigma) of the output level difference between two adjacent effective pixels under no illumination (i.e. dark condition) calculated by the following procedure.



1) Two adjacent pixels (pixel n and n+1) in one reading are fixed as measurement points.
2) Each of the output levels at video output periods averaged over 200 ns period to get V(n) and V(n+1).
3) V(n+1) is subtracted from V(n) to get ΔV.
$\Delta V = V(n) - V(n+1)$
4) The standard deviation of ΔV is calculated after procedure 2) and 3) are repeated 30 times (30 readings).
$$\overline{\Delta V} = \frac{1}{30}\sum_{i=1}^{30}|\Delta Vi| \qquad \sigma = \sqrt{\frac{1}{30}\sum_{i=1}^{30}\left(|\Delta Vi| - \overline{\Delta V}\right)^2}$$
5) Procedure 2), 3) and 4) are repeated 10 times to get sigma value.
6) 10 sigma values are averaged.
$$\bar{\sigma} = \frac{1}{10}\sum_{j=1}^{10}\sigma j$$
7) $\bar{\sigma}$ value calculated using the above procedure is observed $\sqrt{2}$ times larger than that measured relative to the ground level. So we specify the random noise as follows.
$$N_{D\sigma} = \frac{1}{\sqrt{2}}\bar{\sigma}$$

Recommended Operating Conditions (Ta = 25°C)

For best performance, the device should be used within the Recommended Operating Conditions.

Characteristics		Symbol	Min	Typ.	Max	Unit
Clock pulse voltage	"H" level	$V_{\phi 1A}$	4.5	5.0	5.5	V
	"L" level	$V_{\phi 2A}$	0	0	0.5	
Last stage clock pulse voltage	"H" level	$V_{\phi 2B}$	4.5	5.0	5.5	V
	"L" level		0	0	0.5	
Shift pulse voltage	"H" level	V_{SH}	4.5	5.0	5.5	V
	"L" level		0	0	0.5	
Reset pulse voltage	"H" level	V_{RS}	4.5	5.0	5.5	V
	"L" level		0	0	0.5	
Clamp pulse voltage	"H" level	V_{CP}	4.5	5.0	5.5	V
	"L" level		0	0	0.5	
Power supply voltage		V_{OD}	11.4	12.0	13.0	V

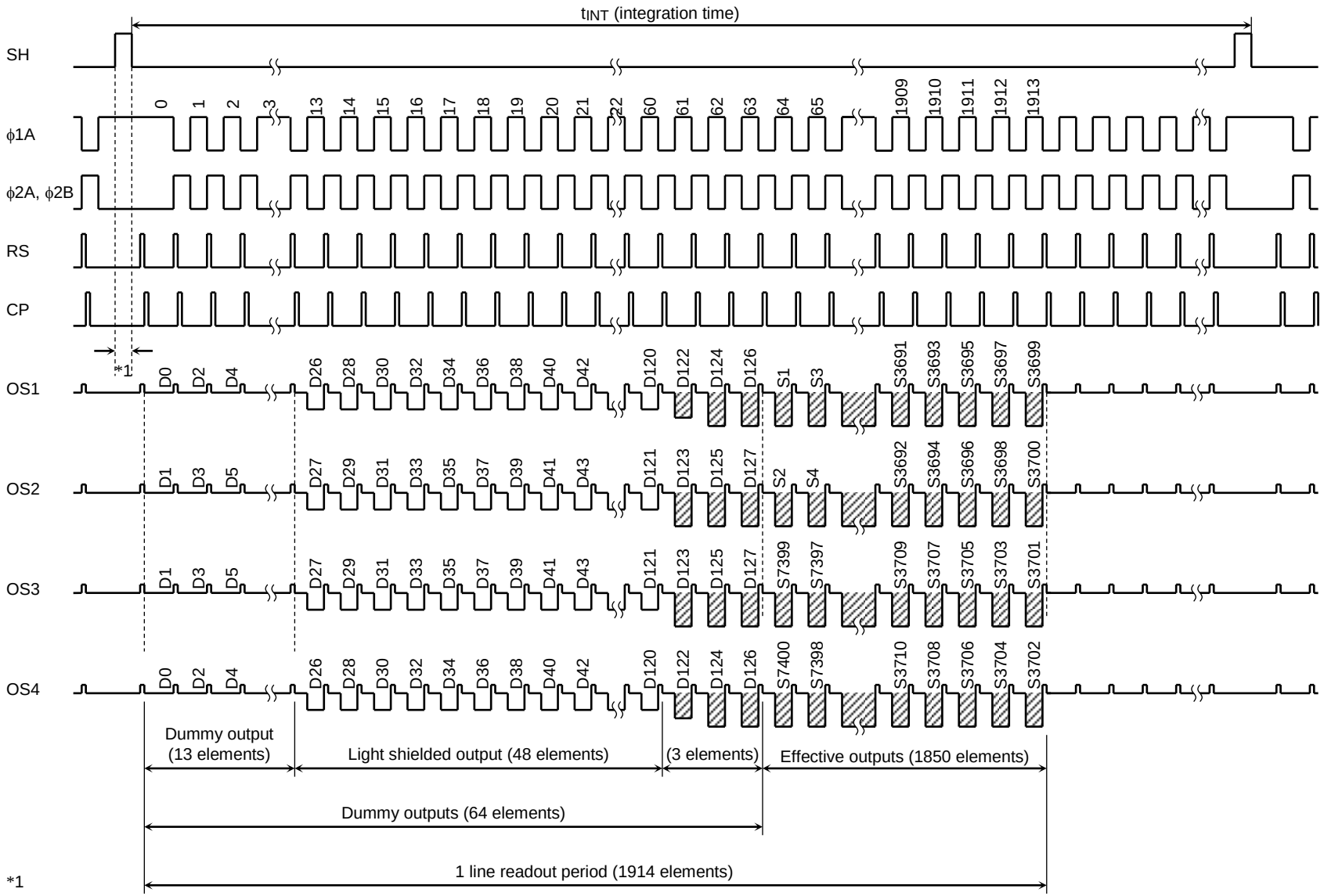
Clock Characteristics (Ta = 25°C)

For best performance, the device should be used within the Recommended Operating Conditions.

Characteristics		Symbol	Min	Typ.	Max	Unit
Clock pulse frequency		f_{ϕ}	—	1	25	MHz
Reset pulse frequency		f_{RS}	—	1	25	MHz
Clamp pulse frequency		f_{CP}	—	1	25	MHz
Clock capacitance	(Note 11)	$C_{\phi 1A}$	—	300	—	pF
		$C_{\phi 2A}$	—	300	—	
Last stage clock capacitance	(Note 11)	$C_{\phi B}$	—	20	—	pF
Shift gate capacitance		C_{SH}	—	50	—	pF
Reset gate capacitance	(Note 11)	C_{RS}	—	20	—	pF
Clamp gate capacitance	(Note 11)	C_{CP}	—	20	—	pF

Note 11: V_{OD} = 12 V, Input capacitance per a pin.

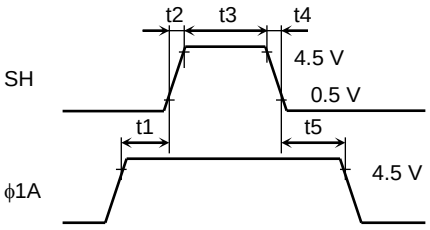
Timing Chart



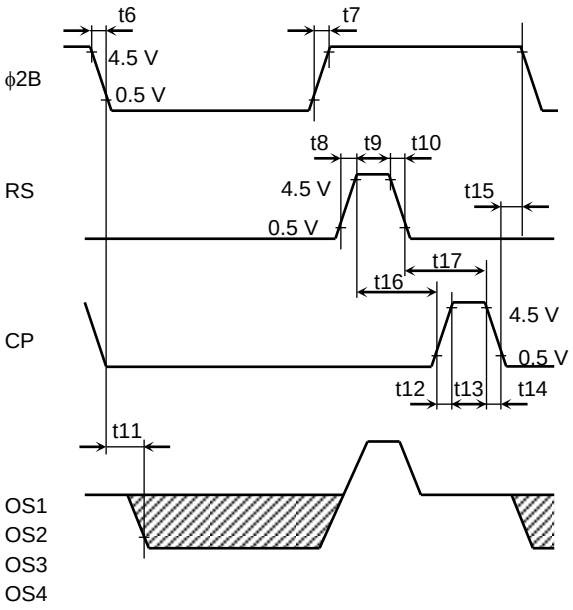
*1
Keep the RS and CP pins “L” level.

Timing Requirements

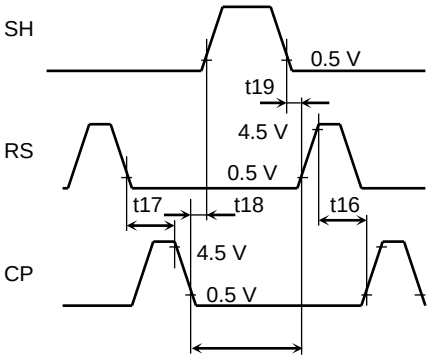
SH, ϕ1 timing



ϕ2, RS, CP, OS timing

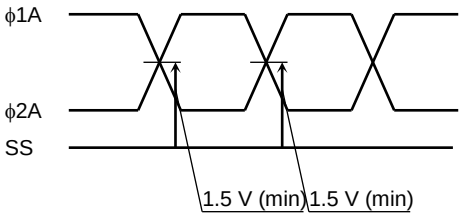


SH, RS, CP timing



(Note 12)

ϕ1, ϕ2 cross point

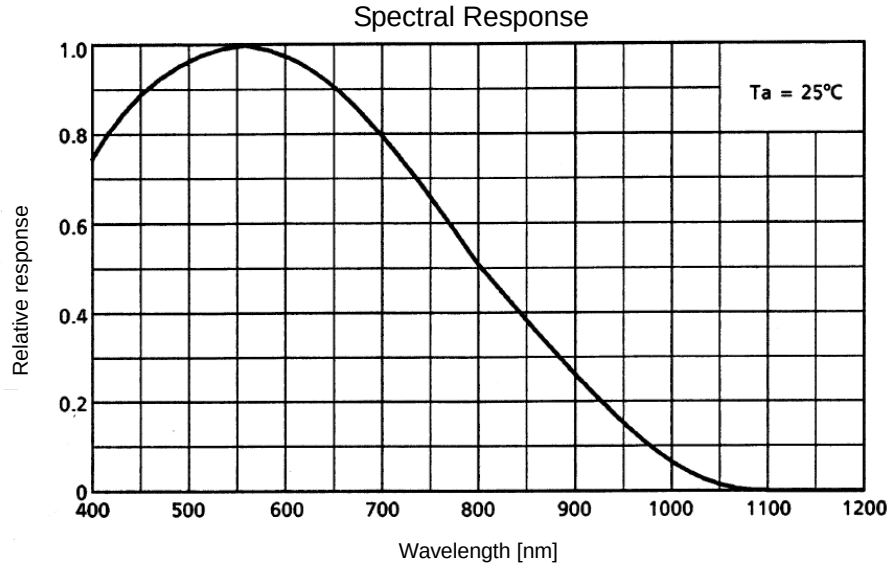


Note 12: Keep the RS and CP pins “L” level.

Characteristics	Symbol	Min	Typ. (Note 13)	Max	Unit
Pulse timing of SH and ϕ1A	t1, t5	200	500	—	ns
SH pulse rise time, fall time	t2, t4	0	50	—	ns
SH pulse width	t3	1000	1500	—	ns
ϕ2B pulse rise time, fall time	t6, t7	0	20	—	ns
RS pulse rise time, fall time	t8, t10	0	20	—	ns
RS pulse width	t9	10	100	—	ns
Video data delay time	t11	—	10	—	ns
CP pulse rise time, fall time	t12, t14	0	20	—	ns
CP pulse width	t13	10	200	—	ns
Pulse timing of ϕ2B and CP	t15	0	50	—	ns
Pulse timing of RS and CP	t16	0	0	—	ns
	t17	10	100	—	ns
Pulse timing of SH and CP	t18	200	—	—	ns
Pulse timing of SH and RS	t19	200	—	—	ns

Note 13: Measured with f_{RS} = 1 MHz.

Typical Spectral Response



Cautions

1. Electrostatic Breakdown

Store in shorting clip or in conductive foam to avoid electrostatic breakdown.
CCD Image Sensor is protected against static electricity, but inferior puncture mode device due to static electricity is sometimes detected. In handing the device, it is necessary to execute the following static electricity preventive measures, in order to prevent the trouble rate increase of the manufacturing system due to static electricity.

a. Prevent the generation of static electricity due to friction by making the work with bare hands or by putting on cotton gloves and non-charging working clothes.
b. Discharge the static electricity by providing earth plate or earth wire on the floor, door or stand of the work room.
c. Ground the tools such as soldering iron, radio cutting pliers of or pincer.
d. Ionized air is recommended for discharge when handling CCD image sensors.

It is not necessarily required to execute all precaution items for static electricity.
It is all right to mitigate the precautions by confirming that the trouble rate within the prescribed range.

2. Window Glass

The dust and stain on the glass window of the package degrade optical performance of CCD sensor.
Keep the glass window clean by saturating a cotton swab in alcohol and lightly wiping the surface, and allow the glass to dry, by blowing with filtered dry N_2. Care should be taken to avoid mechanical or thermal shock because the glass window is easily to damage.

3. Incident Light

CCD sensor is sensitive to infrared light. Note that infrared light component degrades resolution and PRNU of CCD sensor.

4. Mounting on a PCB

This package is sensitive to mechanical stress.
TOSHIBA recommends using IC inserters for mounting, instead of using lead forming equipment.
Since this package is not strong against mechanical stress, you should not reform the lead frame.
We recommend to use an IC-inserter when you assemble to PCB.

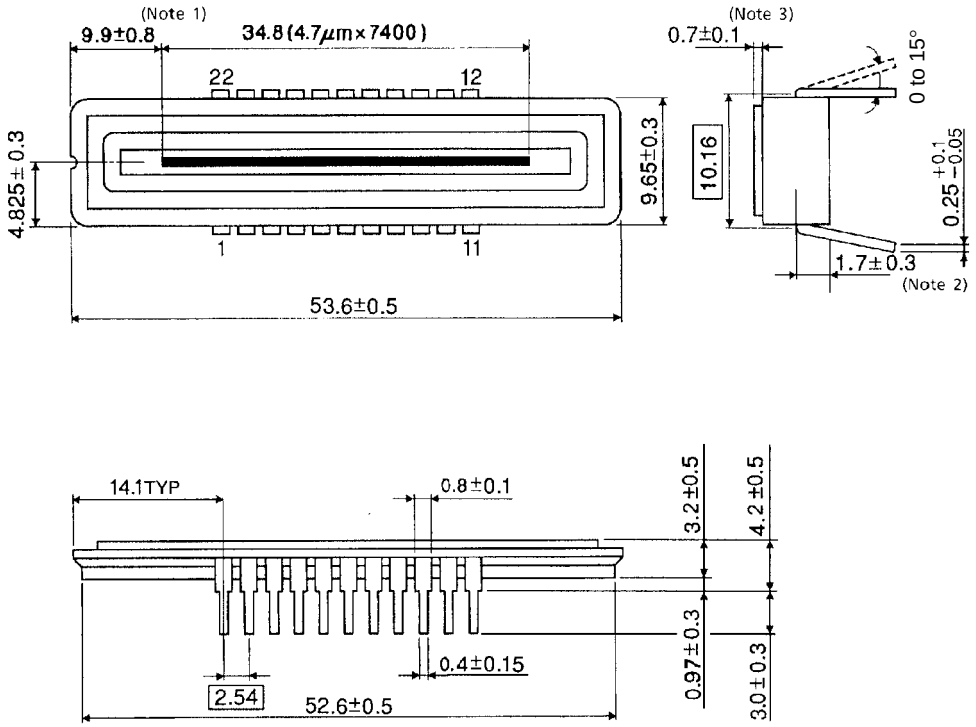
5. Soldering

Soldering by the solder flow method cannot be guaranteed because this method may have deleterious effects on prevention of window glass soiling and heat resistance.
Using a soldering iron, complete soldering within three seconds for lead temperatures of up to 350°C.

Package Dimensions

WDIP22-G-400-2.54E

Unit: mm



Note 1: Distance between the edge of the package and the first pixel (S1)
Note 2: Distance between the top of chip and bottom of the package
Note 3: Glass thickness (n = 1.5)

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